

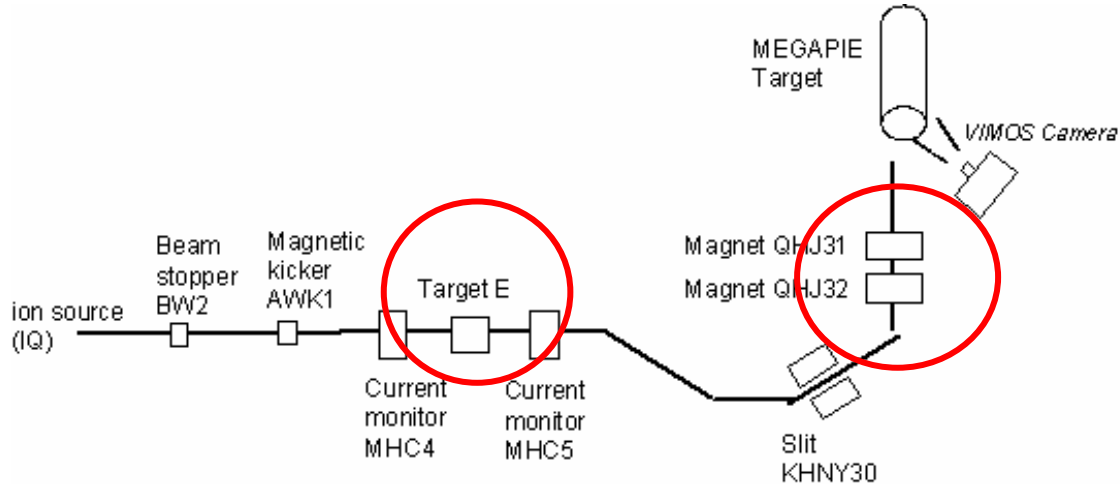
SAFETY EVALUATION OF THE MEGAPIE EXPERIMENTAL FACILITY: RESULTS AND INSIGHTS FROM THE APPLICATION OF PROBABILISTIC SAFETY ASSESSMENT

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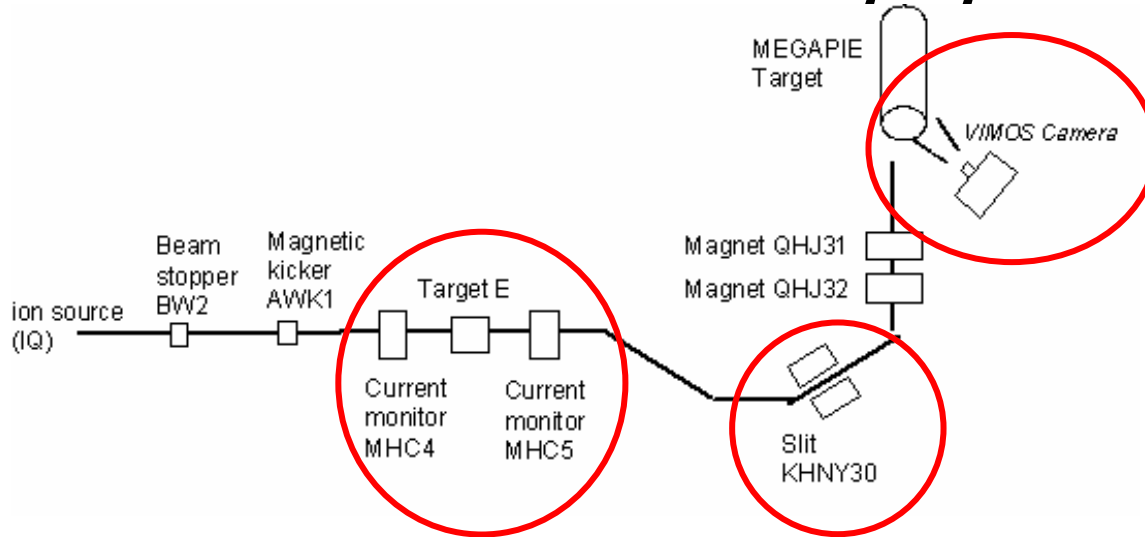
May 7, 2007

Issues for MEGAPIE safety



- **Over-Focused beam** → excessive intensity onto the target → breach of the LMC [MEGAPIE safety report; Smith, 2006]
- “Critical” components to avoid over-focusing are:
 - Scattering **Target E** - diffuses beam intensity distribution
 - Quadrupoles **QJ31-QJ32** - located downstream of two out of three safety systems

MEGAPIE safety systems



- **MHC4/5** – monitors transmission across scattering Target E
- **KHNY30** – limits allowed spread of the trajectory → Detects if protons are correctly scattered by Target E
- **VIMOS** – visually monitors beam intensity distribution

Beam shutdown if parameters are outside allowed range

!!! There are additional safety barriers, e.g. components settings supervisions, that were outside the scope of this analysis

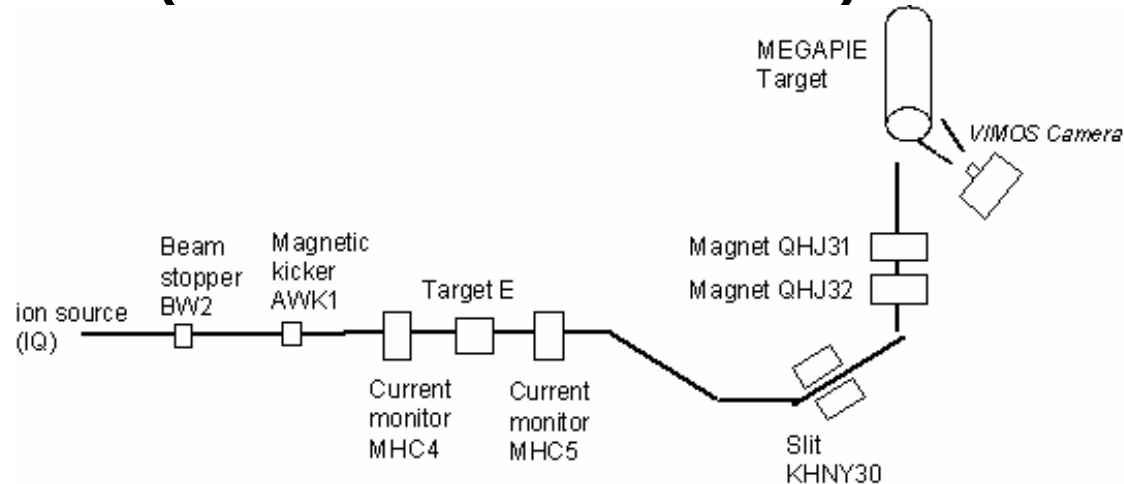
Goals of this study

- Evaluate **redundancy and diversity** of the MEGAPIE safety system
- Suggest possible **safety-enhancing improvements**

 The tool

- Probabilistic safety assessment (**PSA**): methods to **analyze** systems, **model** scenarios and failures, **calculate** risk and its contributors
 - “event trees and fault trees”

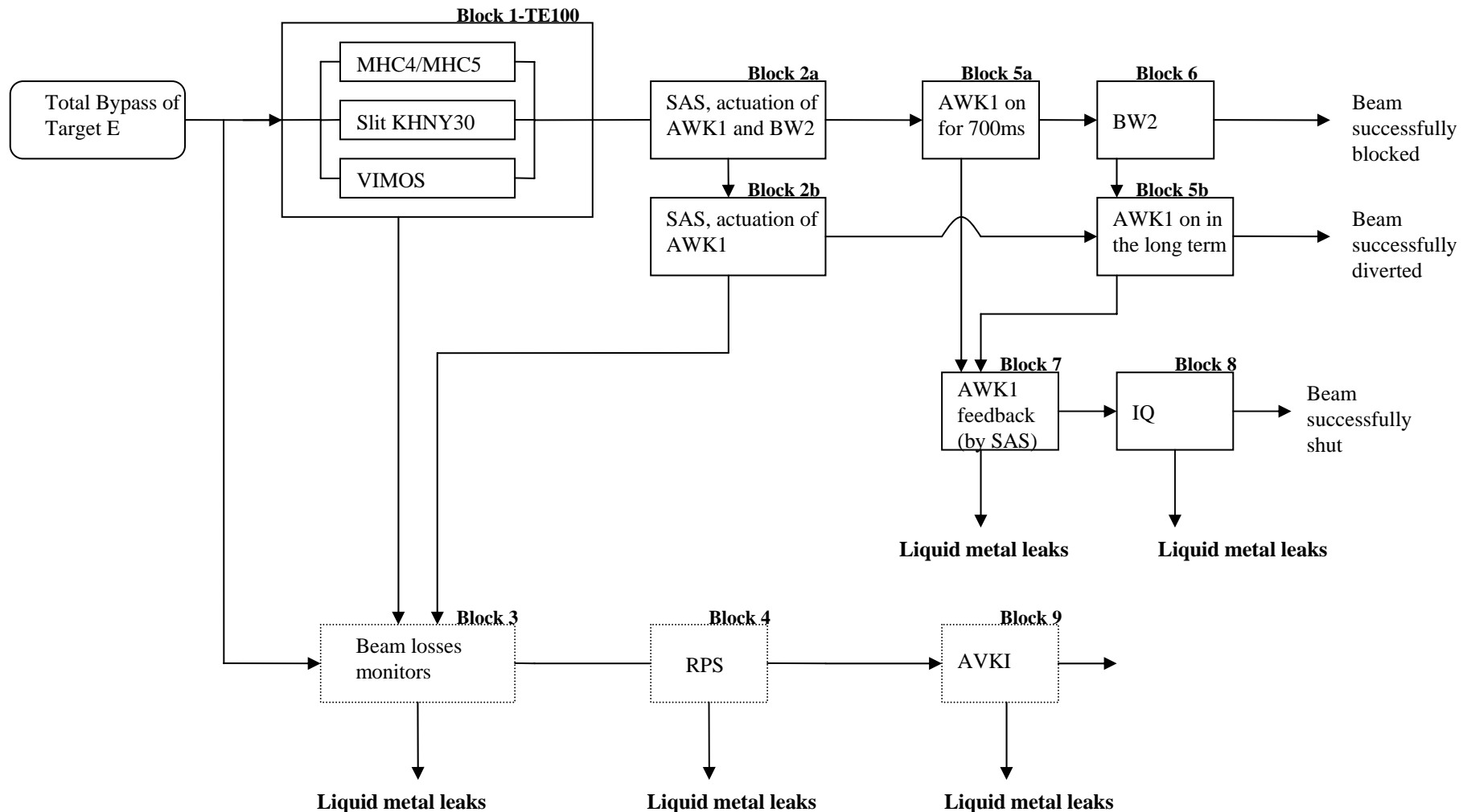
Initiating events (How accidents start)



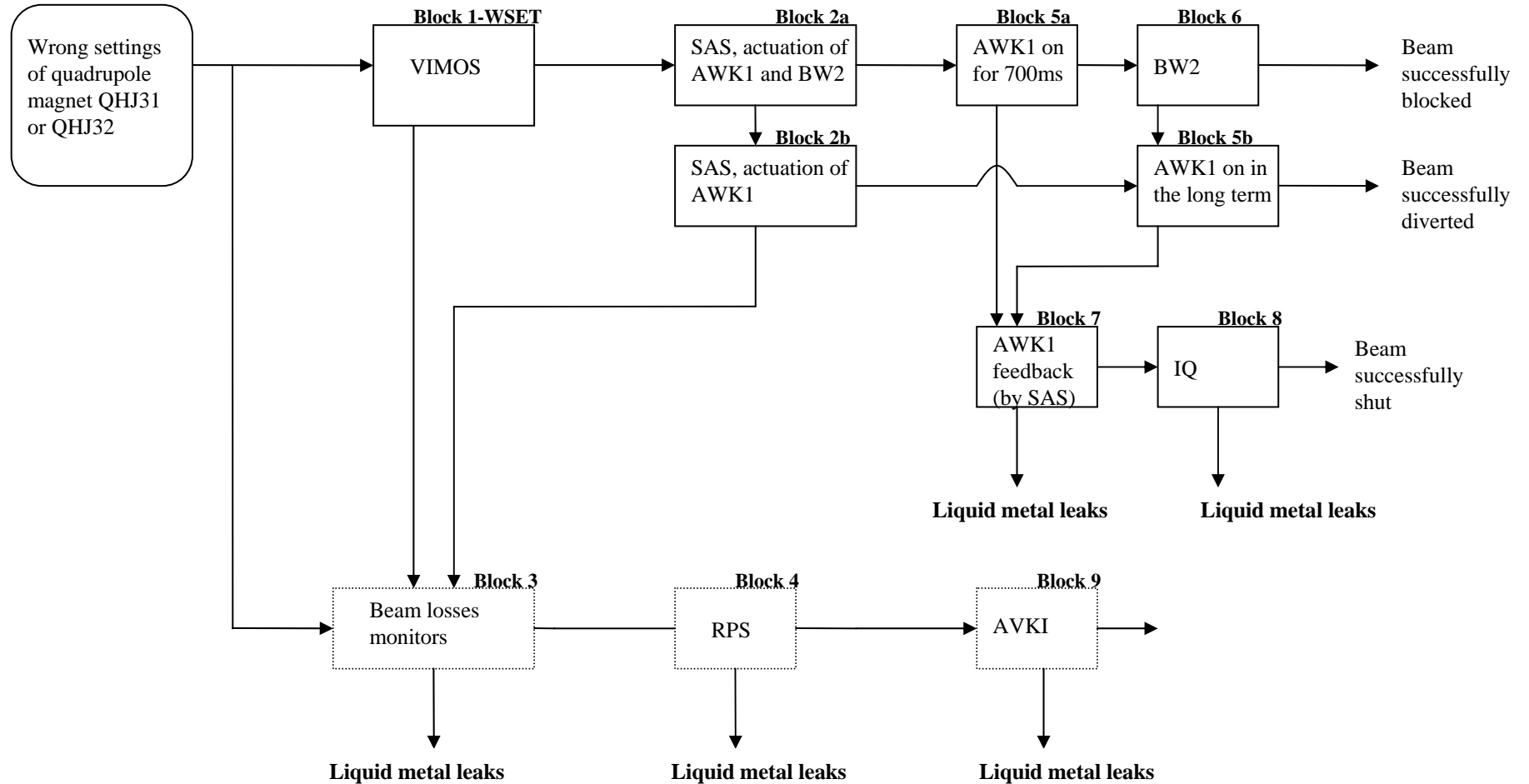
- Three events potentially initiating an accident of excessive beam over-focus:
 - **TE-BY** - total bypass of Target E by protons beam
 - **WSET1** - Wrong settings of QHJ31 or QHJ32. Wrong settings loaded into the components control devices
 - **WSET2** - Wrong settings of QHJ31 or QHJ32. Magnets failure to set or of control devices to command current

Model of scenario TE-BY

Event sequence diagrams: required functions and systems



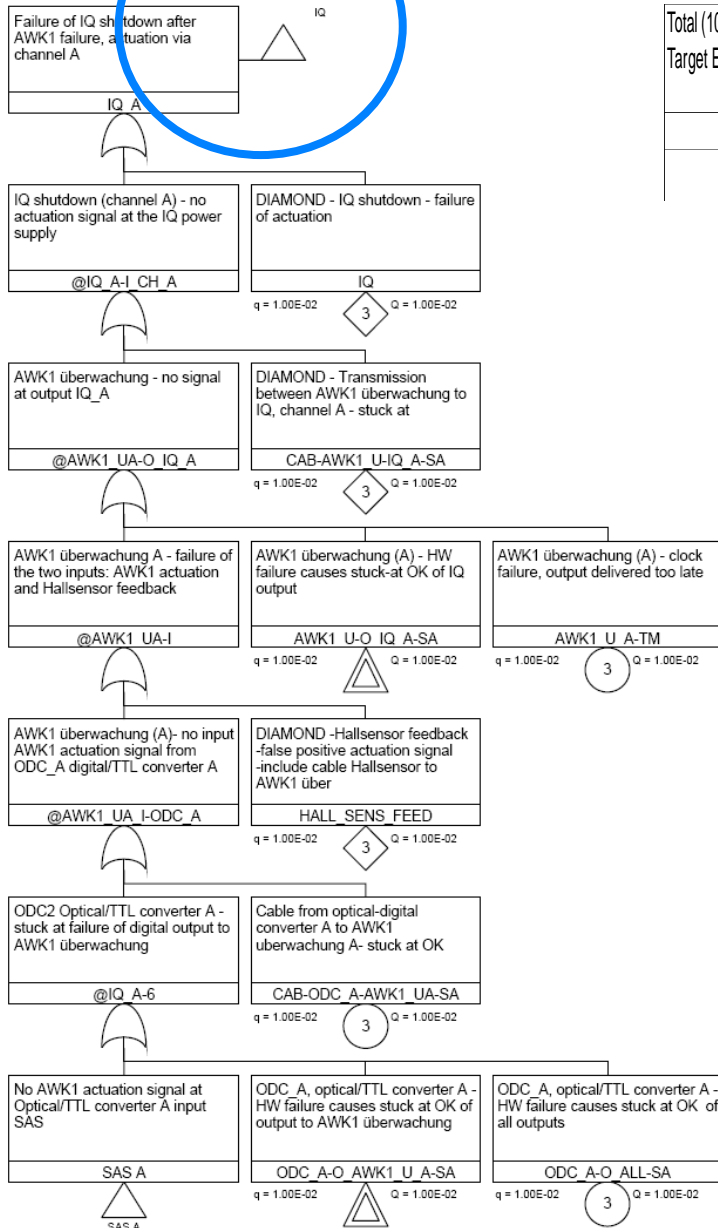
Model of scenario WSET1



Model of scenario TE-BY

Event Trees: sequence of functions and systems

| Total (100%) bypass of Target E | MHC4/5, KNY30, VIMOS | MEGAPE and SINQ SAS | BW2 shutter | AWK1 operates at least 700 ms | AWK1 operates in the long term | AWK1 feedback and IQ shutdown n | beam losses monitors and RPS | No. | Conseq. | Code |
|---------------------------------|----------------------|---------------------|-------------|-------------------------------|--------------------------------|---------------------------------|------------------------------|-----|---------|-------------------|
| TE-BY | SENSORS-TE-BY | SAS | BW2 | AWK1/700 | AWK1 | IQ | RPS | | | |
| | | | | | | | | 1 | SUCCESS | |
| | | | | | | | | 2 | SUCCESS | AWK1/700 |
| | | | | | | | | 3 | SUCCESS | AWK1/700-IQ |
| | | | | | | | | 4 | FAILURE | AWK1/700-IQ-RPS |
| | | | | | | | | 5 | SUCCESS | BW2 |
| | | | | | | | | 6 | SUCCESS | BW2-AWK1 |
| | | | | | | | | 7 | SUCCESS | BW2-AWK1-IQ |
| | | | | | | | | 8 | FAILURE | BW2-AWK1-IQ-RPS |
| | | | | | | | | 9 | SUCCESS | SAS |
| | | | | | | | | 10 | SUCCESS | SAS-IQ |
| | | | | | | | | 11 | FAILURE | SAS-IQ-RPS |
| | | | | | | | | 12 | SUCCESS | SENSORS-TE-BY |
| | | | | | | | | 13 | FAILURE | SENSORS-TE-BY-RPS |



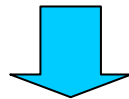
| | | | | | | |
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| TE-BY | SENSORS-TE-BY | SAS | BW2 | AWK1/700 | AWK1 | IQ |

Fault trees

- **Systematic analysis** of the possible causes of functional failures
- **Functional failures** are systematically traced back to **basic events** failures (ANDs/ORs)
- Basic events: **basic components failure modes** (cables, electronic devices, power supplies, software)

Application of PSA to experimental facilities: challenges

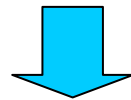
- Use of **digital and software** systems
 - Difficult to **predict** and **quantify** failure modes
 - Timing failures may be difficult to incorporate in fault trees
- Use of one-of-a-kind components
 - **Lack of data** to quantify probabilities of basic events



- Emphasis on **qualitative results** from the PSA
- No attempt to quantify failure events probabilities

What may qualitative results give?

- The PSA model (ETs and FTs) is processed by software (Risk Spectrum®)
- Minimal Cut sets: **sequences of failure events** that may lead to system failure given occurrence of the scenario



It is possible to:

- Identify **single, double, triple, points of failure ...**
- Evaluate adequacy of safety systems (**redundancy and diversity**)
- (Independently on the probability of the sequences)

Results for scenario TE-BY

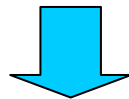
- 6 first-order cutsets (**common cause failures** – i.e. failures of multiple components at the same time)
- **No single point of failure** → MCH4/5, KHNY30, VIMOS constitute a **diverse protection** against scenarios originated by bypass of Target E (TE-BY)

| # | Event | Description |
|---|-------------------|---|
| 1 | OPT_PAN1-O_ALL-SA | Optical lead panel 1 - common cause stuck at failure of all outputs, due to loss of isolation |
| 2 | OPT_PAN2-O_ALL-SA | Optical lead panel 2 - common cause stuck at failure of all outputs, due to loss of isolation |
| 3 | S_SAS_A_B-CCF-ALL | SINQ SAS A and B - Common cause stuck at OK |
| 4 | M_SAS_A_B-CCF-ALL | MEGAPIE SAS A and B - Common cause stuck at OK |
| 5 | DOC_A_B-CCF-ALL | DOC, TTL/optical converters A and B - Common cause stuck at OK |
| 6 | ODC_A_B-CCF-ALL | ODC, optical/TTL converters A and B - Common cause stuck at OK |

Results for scenario WSET1

- 16 first-order cutsets (10 related to failures of the VIMOS system)
- **Relevant safety contribution of VIMOS:** it is the only monitoring system able to catch WSET1
- VIMOS is devised with **multiple protections** against several failure modes
- Two Failure events identify scenarios where VIMOS would continue to evaluate the same frame, not recognizing a disturbance in the beam intensity distribution:

| Event identifier | Description |
|--------------------|--|
| VIMOSSW-SA | VIMOS SW - stuck at while executing due to programming error or operating system failure |
| FRAMEGRR-BUFFER-SA | Frame Grabber - memory buffer stuck-at due to buffer failure or software failure to save new picture |



Specific safety-enhancing recommendations

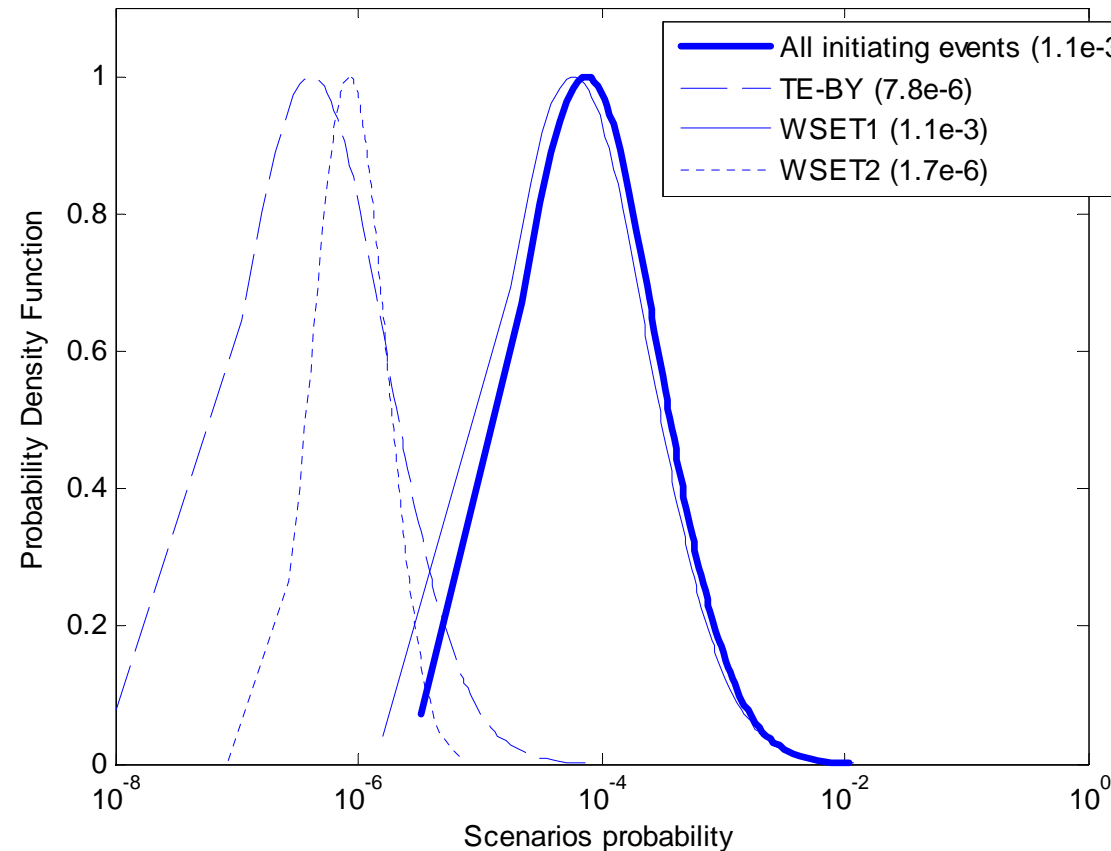
Recommendations

- Two (additional) recommendations to make sure VIMOS is actively processing valid pictures:
 - Implement an automatic check (e.g. control on signal variance)
 - Formalize daily routine checks in the control room

Yet, quantification has benefits (in conference Paper)

PSA handles uncertainties !!

- Prioritize scenarios, components, failure modes based on their impact on risk
- Prioritize recommendations based on their potential for risk-reduction



Conclusions

- PSA can provide safety insights and identify measures for informing designers of the safety of experimental installations
- Lack of data is certainly a challenge but should not discourage (PSA treats uncertainties)
- Prioritize the identification of weaknesses, rather than the value of the risk

**Shifts the focus
from probabilities
to understanding risk**

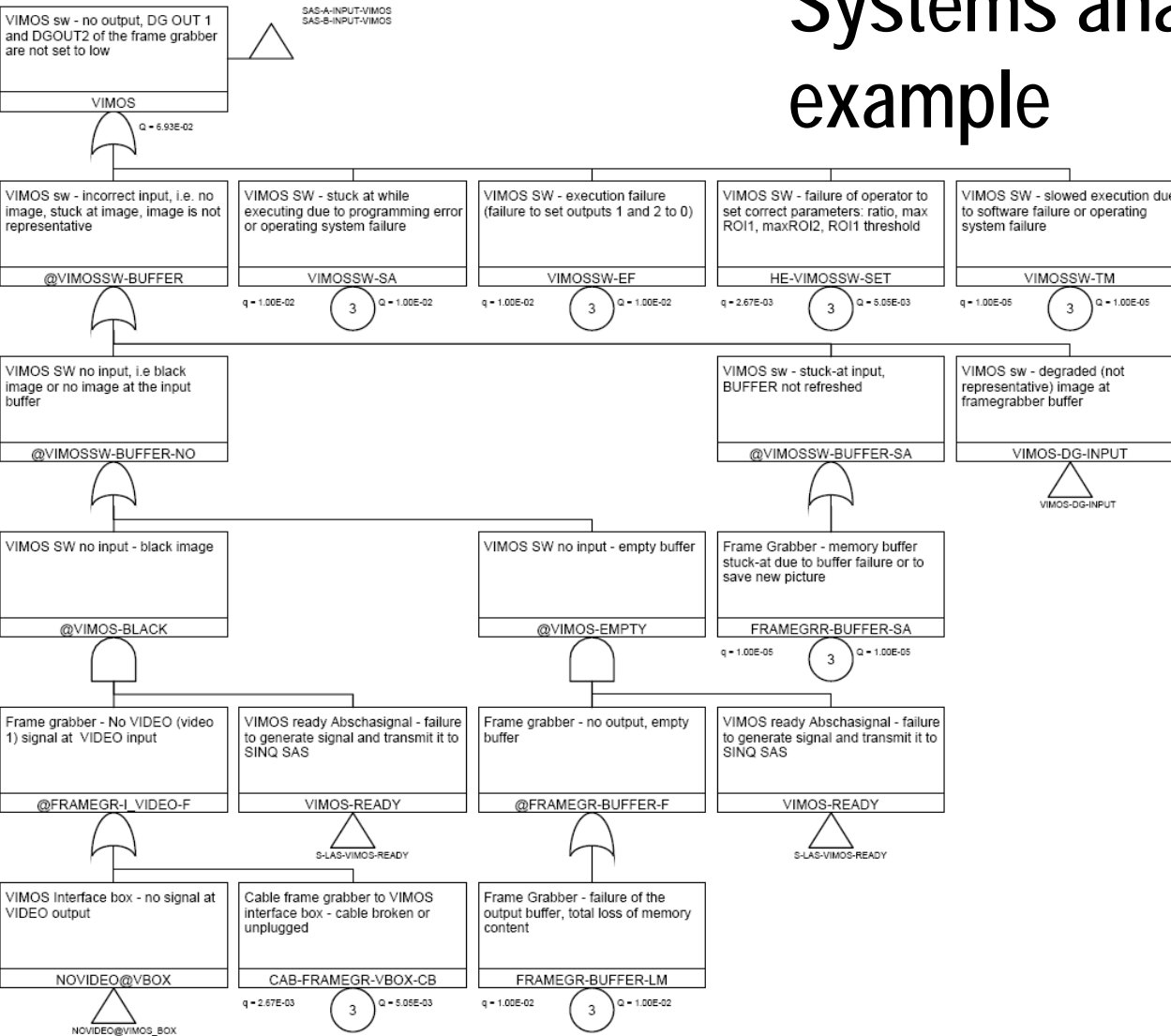
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Job openings in our group at PSI! Go to <http://safe.web.psi.ch/>

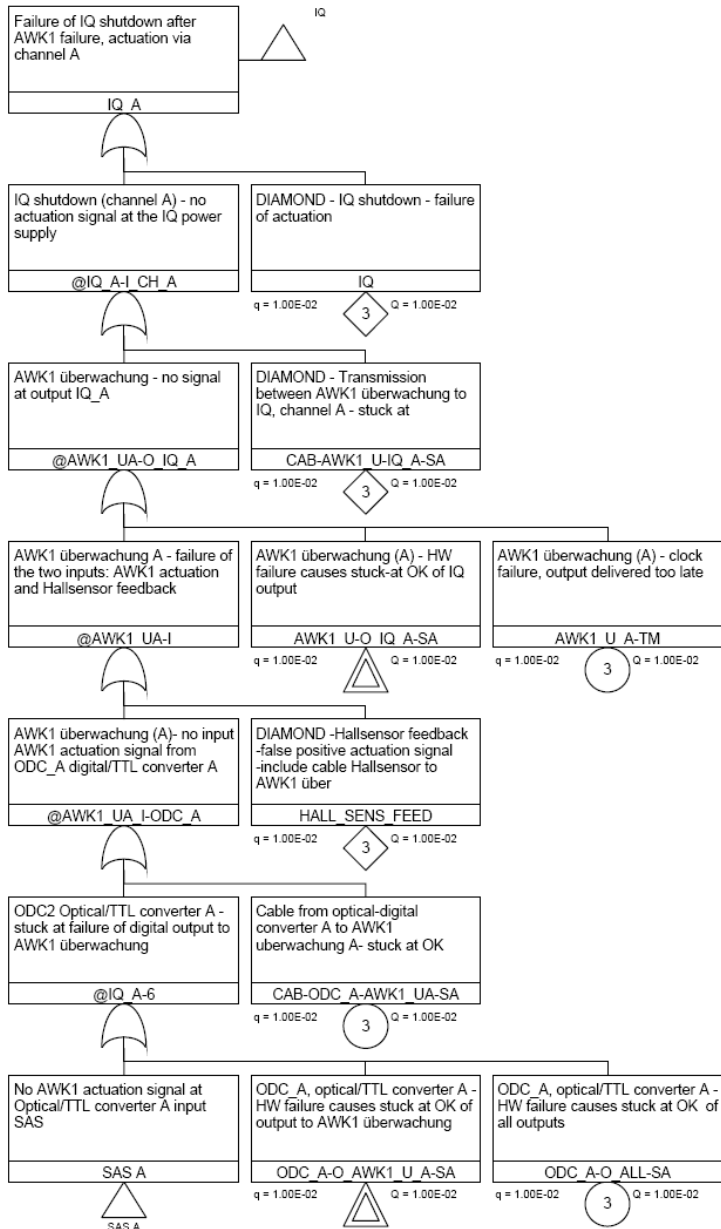
Systems analysis – Fault trees, example



Failure modes for pc-based software (VIMOS)

- Challenging failure modes: part of the PC, SW, OP sys fail while other still function
- VIMOS software loads and processes over and over the same image (frame grabber memory failure).
- The VIMOS software fails to load new images with the result that it processes over and over the same image.

Systems analysis – Fault trees,



- Challenge: Failure modes analysis for digital devices:
 - No output: i.e. signal goes to zero
 - Stuck at output: the signal does not switch to the correct output value when needed
 - Timing failure: output of the device is delivered too late (internal clock failure)
 - Wrong parameters set: parameters (e.g. thresholds for signal comparison, timing limits) are set to wrong values.